

Search only in: Engineering, Computer Science, and Mathematics Physics, Astronomy, and Planetary Science Search in all subject areas.**Scholar All articles - Recent articles Results 1 - 20 of about 548 for transient quiescent current fa****Defect Detection with Transient Current Testing and its Potential for Deep Sub-micron CMOS ICs**

M Sachdev, P Janssen, V Zieren - Proceedings of the 1998 IEEE International Test Conference, 1998 - doi.ieeecs.org

... equally important to find out which transient current segments are ... device provides the key for fault detection ... only the peak and the quiescent current level of ...

Cited by 78 - Related articles - Web Search - All 5 versions

Transient power supply current testing of digital CMOS circuits

RZ Makki, ST Su, T Nagle - Test Conference, 1995. Proceedings., International, 1995 - ieeexplore.ieee.org

... assume that the normal dynamic (transient) current ... is distinguishably higher than the quiescent current ZDD ... the absence of the iDD pulse indicates a fault. ...

Cited by 70 - Related articles - Web Search - BL Direct - All 2 versions

Quiescent power supply current measurement for CMOS IC defectdetection

CF Hawkins, JM Soden, RR Fritzeimeier, LK Horning - Industrial Electronics, IEEE Transactions on, 1989 - ieeexplore.ieee.org

... that exists in a CMOS circuit when all logic states have settled and are in a steady state or quiescent mode. Transient power supply current is the ...

Cited by 89 - Related articles - Web Search - All 4 versions

Transient Current Testing of 0.25 µm CMOS Devices

B Kruseman, P Janssen, V Zieren - Proceedings of the 1999 IEEE International Test Conference, 1999 - doi.ieeecomputersociety.org

... wait till the current has reached the quiescent level for ... to determine the total charge in a transient peak instead ... 18] integrated the i DD current and compare ...

Cited by 54 - Related articles - Web Search - BL Direct - All 4 versions

Built-in current testing of integrated circuits

WP Maly, PJ Nigh - US Patent 5,025,344, 1991 - freepatentsonline.com

... 50, 100 and 150 nanoseconds, a large transient current occurs then ... The quiescent value may vary for different IC circuits ... 6 shows current flow with a gate oxide ...

Cited by 33 - Related articles - Web Search - All 13 versions

CURRENT VS. LOGIC TESTING OF GATE OXIDE SHORT, FLOATING GATE AND BRIDGING FAILURES IN CMOS

R Rodriguez-Montanes, JA Segura, VH Champac, J ... - Test Conference, 1991. Proceedings., International, 1991 - ieeexplore.ieee.org

... shown that some failure mechanisms exhibit a transient behaviour, in t ... current is; expressed in PA (in a fault-free circuit this quiescent current is in ...

Cited by 75 - Related articles - Web Search - All 2 versions

Built-in current testing-feasibility study - ►sigda.org [PDF]

W Maiy, P Nigh - Computer-Aided Design, 1988. ICCAD-88. Digest of Technical ..., 1988 - ieeexplore.ieee.org
... the boundary between normal and abnormal quiescent currents ... the voltage drop during peak transient currents ... Compare the voltage across the current Sensor of the ...
Cited by 186 - Related articles - Web Search - All 6 versions

Transient power supply current monitoring—A new test method for CMOS VLSI circuits
ST Su, RZ Maikki, T Nagle - Journal of Electronic Testing, 1995 - Springer
... Design for current-testability, drain/source opens, floating gates, shorts, transient power supply ... IDD Q (quiescent power supply current) testing has ...
Cited by 56 - Related articles - Web Search - BL Direct - All 2 versions

Quiescent current analysis and experimentation of defective CMOS circuits
JA Segura, VH Champac, R Rodriguez-Montañés, J ... - Journal of Electronic Testing, 1992 - Springer
... In the field using Inductive Fault Analysis [1], [2] ... Limited experimental data on quiescent current meas- ures are ... of the influence of defect characteristics on ...
Cited by 35 - Related articles - Web Search - All 2 versions

Detection and location of faults and defects using digital signal processing
C Thibeault - VLSI Test Symposium, 1995 - doi.ieeecs.org
... be useful for tech- nologies with significant quiescent current, since their ... ples (once per clock period) current when ICs ... when the chips are in transient state ...
Cited by 33 - Related articles - Web Search - All 6 versions

Increased CMOS IC stuck-at fault coverage with reduced I DDQ test sets
RR Fritzemeier, JM Soden, RK Treece, CF Hawkins - Test Conference, 1990. Proceedings., International, 1990 - ieeexplore.ieee.org
... produce elevated quiescent current in one or more logic states. ... logic 0 and 1 (non-transient logic states ... The difference in untestable fault counts between the ...
Cited by 69 - Related articles - Web Search

Defect Detection Using Power Supply Transient Signal Analysis - ►umbc.edu [PDF]
A Germida, Z Yan, JF Plusquellec, F Muradali - INTERNATIONAL TEST CONFERENCE, 1999 - doi.ieeecomputersociety.org
... on the analysis of a circuit's parametric properties, for example, propagation delay, magnitude of quiescent supply current or transient response [5 ...
Cited by 46 - Related articles - Web Search - BL Direct - All 7 versions

Built-in current sensor for I DDQ test in CMOS
CW Hsue, CJ Lin - Test Conference, 1993. Proceedings., International, 1993 - ieeexplore.ieee.org
... requirement of large current sink for state-transition transient current. ... RR Fritzemeier and LK Homing, "Quiescent power supply current measurement for ...
Cited by 27 - Related articles - Web Search - BL Direct - All 2 versions

Defect-oriented test methodology for complex mixed-signal circuits
FOM Kuijstermans, M Sachdev, AP Thijssen - European Design and Test Conference, 1995. ED&TC 1995, ..., 1995 - ieeexplore.ieee.org
... can be detected by simple DC, Transient and AC ... due to a leakage current, the quiescent current is strongly ... Defect simulation and fault collapsing The defect sim ...
Cited by 21 - Related articles - Web Search - All 9 versions

Electrical Model of the Floating Gate Defect in CMOS IC's: Implications on I- D- D- Q Testing
VH Champac, A Rubio, J Figueras - IEEE TRANSACTIONS ON COMPUTER AIDED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS, 1994 - ieeexplore.ieee.org
... chip with transistors possessing floating gate defects. ... characteristics of both the fault-free transistor ... which produces the same equivalent quiescent current. ...

Cited by 71 - Related articles - Web Search - BL Direct - All 3 versions

Transient current testing based on current (charge) integration

I de Paul, R Picos, JL Rossello, M Roca, E Isern, ... - IDDQ Testing, 1998. Proceedings. 1998 IEEE International ... 1998 - ieeexplore.ieee.org

... consumption not only during the quiescent periods, but ... Since this technique monitors the transient current, the test ... were chosen to induce a current path in ...

Cited by 10 - Related articles - Web Search - All 3 versions

Experimental analysis of transient current testing based on chargeobservation

J Segura, I De Paul, M Roca, E Isern, CF Hawkins - Electronics Letters, 1999 - ieeexplore.ieee.org ... current and changed only the transient part of the ... charge value was beyond the fault free charge ... Open circuits causing quiescent current elevation in latch ...

Cited by 7 - Related articles - Web Search - BL Direct - All 3 versions

IDDQ testing of CMOS opens: an experimental study

AD Singh, H Rasheed, WW Weber - Test Conference, 1995. Proceedings., International, 1995 - ieeexplore.ieee.org

... a stable state following a switching transient. Any quiescent current drawn from the power rails, beyond the background junction leakage current, indicates a ...

Cited by 40 - Related articles - Web Search - BL Direct - All 2 versions

A 2-ns detecting time, 2- μ m CMOS built-in current sensingcircuit

TL Shen, JC Daly, JC Lo - Solid-State Circuits, IEEE Journal of, 1993 - ieeexplore.ieee.org ... minimum of 2-ns duration of quiescent power supply current (without excessive transient current) is needed for an accurate current testing result ...

Cited by 43 - Related articles - Web Search - BL Direct - All 3 versions

Current sensing for built-in testing of CMOS circuits

DBI Feltham, PJ Nigh, LR Carley, W Maly - Computer Design: VLSI in Computers and Processors, 1988. 1988 - ieeexplore.ieee.org

... In such circuits, peak values of transient currents are ... faulty and "fault-free" quiescent currents. ... simulations, one can estimate current differences smaller ...

Cited by 39 - Related articles - Web Search

Key authors: J Soden - C Hawkins - W Maly - V Champac - J Figueras

Google ►

Result Page: 1 2 3 4 5 6 7 8 9 10 Next

transient quiescent current fault defe

[Google Home](#) - [About Google](#) - [About Google Scholar](#)

©2009 Google

- Search only in: Engineering, Computer Science, and Mathematics
 Physics, Astronomy, and Planetary Science
- Search in all subject areas.

Scholar All articles - Recent articles Results 1 - 20 of about 530 for transient quiescent current fa

Defect Detection with Transient Current Testing and its Potential for Deep Sub-micron CMOS ICs

M Sachdev, P Janssen, V Zieren - Proceedings of the 1998 IEEE International Test Conference, 1998 - doi.ieeecomputersociety.org

... Quiescent current testing (I DQ) is an important ... To prove the fault detection capability of this method ... Because the transient current waveforms may differ in ...

Cited by 76 - Related articles - Web Search - All 5 versions

Quiescent power supply current measurement for CMOS IC defectdetection

CF Hawkins, JM Soden, RR Fritzemeier, LK Horning - Industrial Electronics, IEEE Transactions on, 1989 - ieeexplore.ieee.org

... that exists in a CMOS circuit when all logic states have settled and are in a steady state or quiescent mode. Transient power supply current is the ...

Cited by 89 - Related articles - Web Search - All 4 versions

Transient power supply current testing of digital CMOS circuits

RZ Makki, ST Su, T Nagle - Test Conference, 1995. Proceedings., International, 1995 - ieeexplore.ieee.org

... assume that the normal dynamic (transient) cur- rent ... is dis-tinguishably higher than the quiescent current ZDD ... the absence of the iDDT pulse indicates a fault. ...

Cited by 70 - Related articles - Web Search - BL Direct - All 2 versions

Transient Current Testing of 0.25 μm CMOS Devices

B Kruseman, P Janssen, V Zieren - Proceedings of the 1999 IEEE International Test Conference, 1999 - doi.ieeecomputersociety.org

... wait till the current has reached the quiescent level for ... to determine the total charge in a transient peak instead ... 18] integrated the I DD current and compare ...

Cited by 54 - Related articles - Web Search - BL Direct - All 4 versions

CURRENT VS. LOGIC TESTING OF GATE OXIDE SHORT, FLOATING GATE AND BRIDGING FAILURES IN CMOS

R Rodriguez-Montanes, JA Segura, VH Champac, J ... - Test Conference, 1991. Proceedings., International, 1991 - ieeexplore.ieee.org

... shown that some failure mechanisms exhibit a transient behaviour, in t ... current is; expressed in PA (in a fault-free circuit this quiescent current is in ...

Cited by 75 - Related articles - Web Search - All 2 versions

Defect Detection Using Power Supply Transient Signal Analysis - ► umbc.edu [PDF]

A Germida, Z Yan, JF Plusquellec, F Muradali - INTERNATIONAL TEST CONFERENCE, 1999 - doi.ieeecomputersociety.org

... measurement of an IC's supply current when all nodes have stabilized to a quiescent value. ... Defect Detection using Power Supply Transient Signal Analysis ...

Cited by 46 - Related articles - Web Search - BL Direct - All 7 versions

Quiescent current analysis and experimentation of defective CMOS circuits
JA Segura, VH Champac, R Rodríguez-Montañés, J ... - Journal of Electronic Testing, 1992 - Springer
... In the field using Inductive Fault Analysis [1], [2] ... circuits representative of the
defects investigated ... Limited experimental data on quiescent current meas- ures ...
Cited by 35 - Related articles - Web Search - All 2 versions

Transient power supply current monitoring—A new test method for CMOS VLSI circuits
ST Su, RZ Makki, T Nagle - Journal of Electronic Testing, 1995 - Springer
... denotes the peak value of the quiescent supply current ... directly com- puted from the
transient portion of ... GOOD CKT FAULT CKT Current Response Current Response ...
Cited by 56 - Related articles - Web Search - BL Direct - All 2 versions

Detection and location of faults and defects using digital signal processing
C Thibeault - VLSI Test Symposium, 1995 - doi.ieeecs.org
... be useful for tech- nologies with significant quiescent current, since their ... ples
(once per clock period) current when ICs ... when the chips are in transient state ...
Cited by 33 - Related articles - Web Search - All 6 versions

Built-in current testing-feasibility study - ► sigda.org [PDF]
W Maly, P Nigh - Computer-Aided Design, 1988, ICCAD-88. Digest of Technical ..., 1988 - ieeexplore.ieee.org
... defines the boundary between normal and abnormal quiescent currents ... the voltage drop
during peak transient currents ... in which full adders and current sensors were ...
Cited by 188 - Related articles - Web Search - All 6 versions

IDDQ testing: A review
JM Soden, CF Hawkins, RK Gulati, W Mao - Journal of Electronic Testing, 1992 - Springer
... Abstract. Quiescent power supply current (IDDQ) testing of CMOS ... quality improvement
through increased defect and fault detection is described. ...
Cited by 145 - Related articles - Web Search

Built-in current sensor for I DDQ test in CMOS
CW Hsue, CJ Lin - Test Conference, 1993. Proceedings., International, 1993 - ieeexplore.ieee.org
... requirement of large current sink for state-transition transient current. ... RR Fritzemeier
and LK Homing, "Quiescent power supply current measurement for ...
Cited by 27 - Related articles - Web Search - BL Direct - All 2 versions

A 2-ns detecting time, 2-μm CMOS built-in current sensingcircuit
TL Shen, JC Daly, JC Lo - Solid-State Circuits, IEEE Journal of, 1993 - ieeexplore.ieee.org
... of 2-ns duration of quiescent power supply current (without excessive transient
current) is needed ... and P. Nigh, "Built-in current testing—Feasibility ...
Cited by 43 - Related articles - Web Search - BL Direct - All 3 versions

IDDQ testing of CMOS opens: an experimental study
AD Singh, H Rasheed, WW Weber - Test Conference, 1995. Proceedings., International, 1995 -
ieeexplore.ieee.org
... a stable state following a switch- ing transient. Any quiescent current drawn from
the power rails, beyond the background junction leakage current, indicates a ...
Cited by 40 - Related articles - Web Search - BL Direct - All 2 versions

Current sensing for built-in testing of CMOS circuits
DBI Feltham, PJ Nigh, LR Carley, W Maly - Computer Design: VLSI in Computers and Processors, 1988. . . ,
1988 - ieeexplore.ieee.org
... In such circuits, peak values of transient currents are ... faulty and "fault-free"
quiescent currents. ... simulations, one can estimate current differences smaller ...
Cited by 39 - Related articles - Web Search

Enhancement of resolution in supply current based testing for large ICs
YK Malaya, AP Jayasumana, Q Tong, SM Menon - Proc. IEEE VLSI Test Symp., 1991 -
doi.ieeexplore.ieee.org

... such as NMOS and TTL, the quiescent current can be ... between states, and the noise
in transient current to provide ... the testing of an IC by current measurements. ...

Cited by 26 - Related articles - Web Search - All 3 versions

Electrical Model of the Floating Gate Defect in CMOS IC's: Implications on I_D-D_T-Q Testing
VH Champac, A Rubio, J Figueras - IEEE TRANSACTIONS ON COMPUTER AIDED DESIGN OF INTEGRATED
CIRCUITS, 1994 - ieeexplore.ieee.org

... chip with transistors possessing floating gate defects. ... characteristics of both the
fault-free transistor ... which produces the same equivalent quiescent current. ...

Cited by 71 - Related articles - Web Search - BL Direct - All 3 versions

Increased CMOS IC stuck-at fault coverage with reduced I DDQ test sets

RR Fritzemeier, JM Soden, RK Trece, CF Hawkins - Test Conference, 1990. Proceedings., International, 1990 -
ieeexplore.ieee.org

... produce elevated quiescent current in one or more logic states. ... logic 0 and 1 (non-
transient logic states) ... The difference in untestable fault counts between the ...

Cited by 69 - Related articles - Web Search

Built-in current testing of integrated circuits

WP Maly, PJ Nigh - US Patent 5,025,344, 1991 - freepatentsonline.com

... including radiation induced latch-up or other transient faults. ... may result in still
higher quiescent current flows which ... pads are used while current sensors are ...

Cited by 33 - Related articles - Web Search - All 3 versions

Experimental analysis of transient current testing based on chargeobservation

J Segura, I De Paul, M Roca, E Iseni, CF Hawkins - Electronics Letters, 1999 - ieeexplore.ieee.org

... current and changed only the transient part of ... Open circuits causing quiescent
current elevation in latch ... with this technique; it drew less current than the ...

Cited by 7 - Related articles - Web Search - BL Direct - All 3 versions

Key authors: C Hawkins - J Soden - V Champac - W Maly - J Figueras

Google ►

Result Page: 1 2 3 4 5 6 7 8 9 10 Next

[Google Home](#) - [About Google](#) - [About Google Scholar](#)

©2009 Google



Web Images Video News Maps more »

transient quiescent current fault time integral d | 1950

- 2004

Search

Ad
Sc
Sc

Search only in: Engineering, Computer Science, and Mathematics

Physics, Astronomy, and Planetary Science

Search in all subject areas.

Scholar All articles - Recent articles Results 1 - 20 of about 264 for transient quiescent current fa

Quiescent power supply current measurement for CMOS IC defectdetection

CF Hawkins, JM Soden, RR Fritzemeier, LK Horning - Industrial Electronics, IEEE Transactions on, 1989 - ieeexplore.ieee.org

... quite useful for detecting stuck-at faults themselves using a ... The peak of the transient current is approximately 60 ... in about 100 ns to a low quiescent current. ...

Cited by 89 - Related articles - Web Search - All 4 versions

Transient Current Testing of 0.25 µm CMOS Devices

B Kruselman, P Janssen, V Zieren - Proceedings of the 1999 IEEE International Test Conference, 1999 - doi.ieeecomputersociety.org

... wait till the current has reached the quiescent level for ... to determine the total charge in a transient peak instead ... 18] integrated the IDD current and compare ...

Cited by 54 - Related articles - Web Search - BL Direct - All 4 versions

Detection and location of faults and defects using digital signal processing

C Thibeault - VLSI Test Symposium, 1995 - doi.ieeecs.org

... when the chips are in transient state ... technologies with significant sup- ply quiescent current, since DC ... cir- cuits based on supply current," in International ...

Cited by 33 - Related articles - Web Search - All 6 versions

IDDQ testing: A review

JM Soden, CF Hawkins, RK Gulati, W Mao - Journal of Electronic Testing, 1992 - Springer

... It may seem costly to reject ICs that have in- creased quiescent power supply current but are still per- forming their logic functions ... 4. Fault Detection ...

Cited by 145 - Related articles - Web Search

Test challenges for deep sub-micron technologies - ► acm.org [PDF]

KT Cheng, S Dey, M Rodgers, K Roy - Design Automation Conference, 2000. Proceedings 2000. 37th, 2000 - ieeexplore.ieee.org

... reduction techniques for the application of current testing ... of circuit and more complex fault types (eg ... DFT and test solutions and CAD environment ahead of time. ...

Cited by 73 - Related articles - Web Search - BL Direct - All 17 versions

DELAY TESTING OF DIGITAL CIRCUITS BY OUTPUT WAVEFORM ANALYSIS

P Franco, EJ McCluskey - Test Conference, 1991, Proceedings., International, 1991 - ieeexplore.ieee.org

... and fault-free waveforms before the sampling time, and compared ... required in the past, catastrophic fault models have ... These defects are modeled by delay faults. ...

Cited by 41 - Related articles - Web Search - Library Search - All 2 versions

Defect Detection Using Power Supply Transient Signal Analysis - ► umbc.edu [PDF]

A Germida, Z Yan, JF Plusquellec, F Muradali - INTERNATIONAL TEST CONFERENCE, 1990 - doi.ieeecomputersociety.org

... nodes have stabilized to a quiescent value. ... Defect Detection using Power Supply Transient Signal Analysis ... Several dynamic supply current I DD -based approaches ...

Cited by 46 - Related articles - Web Search - BL Direct - All 7 versions

Built-in current testing of integrated circuits

WP Maly, PJ Nigh - US Patent 5,025,344, 1991 - freepatentsonline.com

... including radiation induced latch-up or other transient faults. ... may result in still higher quiescent current flows which ... pads are used while current sensors are ...

Cited by 33 - Related articles - Web Search - All 3 versions

Enhancement of resolution in supply current based testing for large ICs

YK Malaiya, AP Jayesumana, Q Tong, SM Menon - Proc. IEEE VLSI Test Symp, 1991 - doi.ieeecomputersociety.org

... The width of transient current pulse, loading of VDD pin due to output buffers and ...

Let us assume that the additional quiescent supply current, if, is ...

Cited by 26 - Related articles - Web Search - All 3 versions

Transient current testing based on current (charge) integration

I De Paul, R Picos, JL Rossello, M Roca, E Isern, ... - IDDT Testing, 1998. Proceedings. 1998 IEEE International ... 1998 - ieeexplore.ieee.org

... consumption not only during the quiescent periods, but ... be achieved by measuring the transient current at the ... activity difference between the fault free and ...

Cited by 10 - Related articles - Web Search - All 3 versions

Current sensing for built-in testing of CMOS circuits

DBI Feltham, PJ Nigh, LR Carley, W Maly - Computer Design: VLSI in Computers and Processors, 1988. ... 1988 - ieeexplore.ieee.org

... a forward-biased diode, and appears only during transient current peaks as ... and CF Hawkins, "Measurements of Quiescent Power Supply Current for ChEOS ...

Cited by 39 - Related articles - Web Search

Experimental analysis of transient current testing based on chargeobservation

J Segura, I De Paul, M Roca, E Isern, CF Hawkins - Electronics Letters, 1999 - ieeexplore.ieee.org

... current and changed only the transient part of ... Open circuits causing quiescent current elevation in latch ... with this technique; it drew less current than the ...

Cited by 7 - Related articles - Web Search - BL Direct - All 3 versions

Defect-oriented test methodology for complex mixed-signal circuits

PCM Kuijstermans, M Sachdev, AP Thijssen - European Design and Test Conference, 1995. ED&TC 1995, ... 1995 - ieeexplore.ieee.org

... in a Class AB amplifier can be detected by simple DC, Transient and AC ... in the analog domain, the output of a fault-free circuit ... its quiescent current is zero ...

Cited by 21 - Related articles - Web Search - All 3 versions

Comparison of defect detection capabilities of current-based and voltage-based test methods

- ► iirm.m.fr [PDF]

B Kruseman - European Test Workshop, 2000. Proceedings. IEEE, 2000 - ieeexplore.ieee.org

... over a decade ago when quiescent current testing ... Dynamic current-based tests or transient current testing (IDDT ... For example delay fault testing requires more ...

Cited by 14 - Related articles - Web Search - All 7 versions

Current-Based Testing for Deep-Submicron VLSIs - ► uwwaterloo.ca [PDF]

M Sachdev - IEEE DESIGN & TEST OF COMPUTERS, 2001 - doi.ieeecs.org

... VLSI with very high (>100 mA) quiescent current, the application ... to identify a smooth, monotonic transient-current waveform ... of a deep-micron current-based test ...

Cited by 26 - Related articles - Web Search - BL Direct - All 6 versions

I DDQ testing and defect classes-a tutorial

JM Soden, CF Hawkins - Custom Integrated Circuits Conference, 1995.. Proceedings of ..., 1995 - ieeexplore.ieee.org

... Physical shorts and their related fault models bring to mind an ... ma; seem costly to reject ICs that have increased quiescent power supply current but are ...

Cited by 23 - Related articles - Web Search

...of Defective CMOS Devices Using Correlation and Regression Analysis of Frequency

Domain Transient ... - ► umbc.edu [PDF]

J Plusquellic, D Chiarulli, S Levitan - INTERNATIONAL TEST CONFERENCE, 1997 - doi.ieeecompsociety.org

... all nodes have stabilized to a quiescent value [12 ... Several dynamic supply current

(I DD -based) approaches ... frequency components of the transient signals combine ...

Cited by 28 - Related articles - Web Search - BL Direct - All 11 versions

CMOS Open Defect Detection by Supply Current Test - ► uci.edu [PDF]

M Hashizume, M Ichimiya, H Yotsuyanagi, T Tamesada - Proc. Design, Automation and Test in Europe, 2001 - doi.ieeecompsociety.org

... circuit and is sensitized, large quiescent supply current ... analysis of frequency domain transient signal data ... of Logic Circuits Based on Supply Current Using Auto ...

Cited by 7 - Related articles - Web Search - All 16 versions

Experimental Results on BIC Sensors for Transient Current Testing

R Picos, M Roca, E Isern, J Segura, E Garcia- ... - Journal of Electronic Testing, 2000 - Springer

... the activation of the faults by enabling or ... In sensor based on transient current integration (charge) show ... defects raising the quiescent current consumption (I ...

Cited by 7 - Related articles - Web Search - BL Direct - All 9 versions

Built-in current sensor for/spl Delta//sub DDQ/testing - ► upc.es [PDF]

JR Vazquez, J Pineda de Gyvez - Solid-State Circuits, IEEE Journal of, 2004 - ieeexplore.ieee.org

... 2 by the current source and the capacitance) is in the quiescent state, then ... operating mode, the switch is closed and in each transient, a voltage ...

Cited by 13 - Related articles - Web Search - BL Direct - All 4 versions

Key authors: [C Hawkins](#) - [J Soden](#) - [R Gulati](#) - [P Nigh](#) - [K Cheng](#)

Google ►

Result Page: 1 2 3 4 5 6 7 8 9 10 Next

[Google Home](#) - [About Google](#) - [About Google Scholar](#)

©2009 Google